

Uncertainty source	Type	Effect on simulated signal yield
Integrated luminosity	Normalization	2.3–2.5%
Muon efficiency	Normalization	1%
Muon energy scale	Shape	<0.3%
Electron efficiency	Normalization	2–3%
Electron energy scale	Shape	<0.3%
Tracking efficiency	Normalization	4.6–4.8%
Ditrack isolation efficiency	Normalization	2%
Ditrack isolation efficiency extrapolation	Shape	1–6%
Production cross sections	Normalization	0.4–3.9%
Choice of PDF and α_S	Normalization	1.6–3.2%
Inelastic cross section	Shape	0.5–1.5%
Limited size of simulated samples	Shape	Bin-dependent